

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE		ATTY. DOCKET NO. S00-086/US	SERIAL NO. 09/925,278
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Subbhasish Mitra	
		FILING DATE 8/8/2001	GROUP 2133

U.S. PATENT DOCUMENTS

INITIAL		DOCUMENT NUMBER							DATE	NAME	RELEVANT INFORMATION
RSD	A	4	3	7	5	6	8	3	03/01/1983	Wensley	37136
RSD	B	4	0	1	7	7	4	2	04/12/1977	James	307/357
RSD	C	6	0	4	4	4	8	7	03/28/2000	Li	714/797
RSD	D	5	0	8	4	8	7	8	06/28/1992	Kanekawa et al.	371/36
RSD	E	3	6	8	1	5	7	8	08/01/1972	Stevens	235/53
RSD	F	4	8	7	3	6	8	5	10/10/1998	Milis Jr.	371/36
RSD	G	4	0	9	1	2	9	3	05/23/1978	Ando	307/205
RSD	H	6	0	4	4	4	8	6	03/28/2000	Underseth et al.	714/797
RSD	I	5	9	9	5	5	5	9	11/30/1999	Hedberg	375/479
RSD	J	5	7	1	9	8	7	1	02/17/1998	Helm et al.	370/479
RSD	K	5	5	0	2	7	2	8	03/26/1996	Smith III	395/182.03

FOREIGN PATENT DOCUMENTS

	2-letter code	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

L	[De Sousa 78] De Sousa, P.T., and F.P. Mathur, "Sift-Out-Modular Redundancy," IEEE Trans. Computers, Vol. C-27, No. 7, pp. 624-627, July 1978
M	[Dennis 74] Dennis, N. G., "Ultra-reliable Voter Switches with a Bibliography of Mechanization," Microelectronics and Reliability, pp. 299-308, August 1974
N	[Gersting 91] Gersting, J. L., et al., "A Comparison of Voting Algorithms for N-Version Programming," Proc. Annual Hawaii Intl. Conf. on System Sciences, pp. 253-262, 1991.
O	[Lala 94] Lala, J. H. and R. E. Harper, "Architectural Principles for Safety-critical Real-time Applications," Proc. of the IEEE, Vol. 82, No. 1, pp. 25-40, Jan. 1994.
P	[Mitra 99] Mitra, S., N. R. Saxena and E. J. McCluskey, "A Design Diversity Metric and Reliability Analysis for Redundant Systems," Proc. Intl. Test Conf., pp. 662-671, 1999.
Q	[Mitra 00] Mitra, S., and E. J. McCluskey, "Design of Redundant Systems Protected Against Common-Mode Failures," Technical Report, Center for Reliable Computing, Stanford Univ., CRC-TR-00-2, 2000. (http://crc.stanford.edu)
R	[Reed 97] Reed, R., et al., "Heavy Ion and Proton-Induced Single Event Multiple Upset," IEEE Trans. on Nuclear Science, Vol. 44, No. 6, pp. 2224-2229, July 1997.



		[Siewiorek 75] Siewiorek, D. P., "Reliability Modeling of Compensating Module Failures in Majority Voted Redundancy," <i>IEEE Trans. Computers</i> , Vol. 24, No. 5, pp. 525-533, 1975.
		[Siewiorek 92] Siewiorek, D. P. and R. S. Swarz, <i>Reliable Computer Systems: Design and Evaluation</i> , Digital Press, 1992.
	U	[TI 76] <i>The TTL Data Book</i> , Texas Instruments, 1976.
	V	[Trivedi 82] Trivedi, K.S., <i>Probability and Statistics with Reliability, Queuing, and Computer Science Applications</i> , Prentice Hall, Englewood Cliffs, NJ, USA, 1982.
	W	[Von Neumann 56] Von Neumann, J., "Probabilistic Logics and the Synthesis of Reliable Organisms from Unreliable Components," <i>Automata Studies, Ann. of Math. Studies</i> , no. 34, C. E. Shannon and J. McCarthy, Eds., Princeton University Press, pp. 43-98, 1956.
	X	[Wong 96] Wong, K., et al., "A VLSI Median Voter for Fault Tolerant Signal Processing Applications," <i>Proc. Intl. Conf. Signal Processing</i> , pp. 1574-1577, 1996.

EXAMINER

R. Stephen Dildine

DATE CONSIDERED

12 Nov. 2004

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.